

Ewald Konstruktion

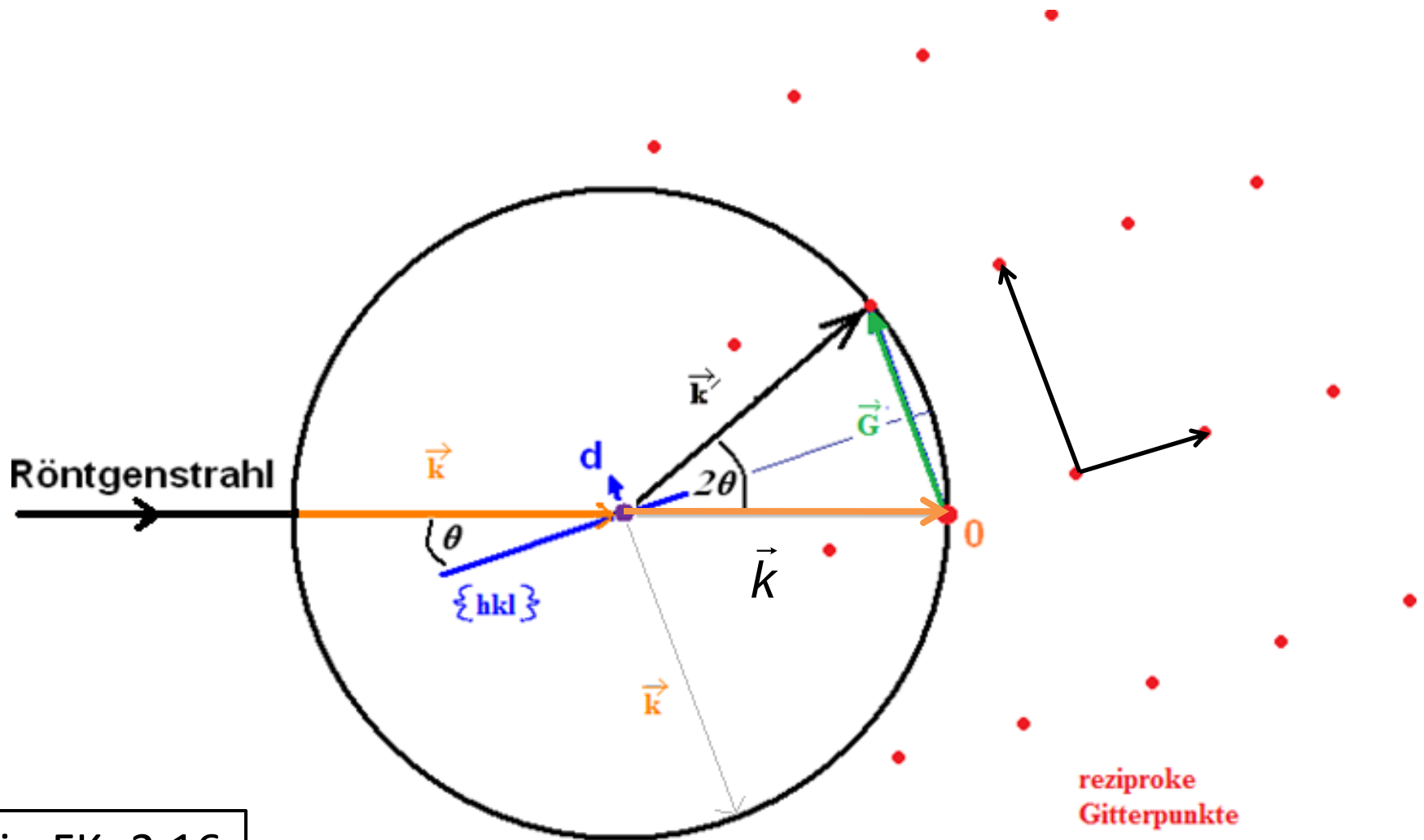


Fig-FK- 2.16

Strukturfaktor und mehratomige Basis

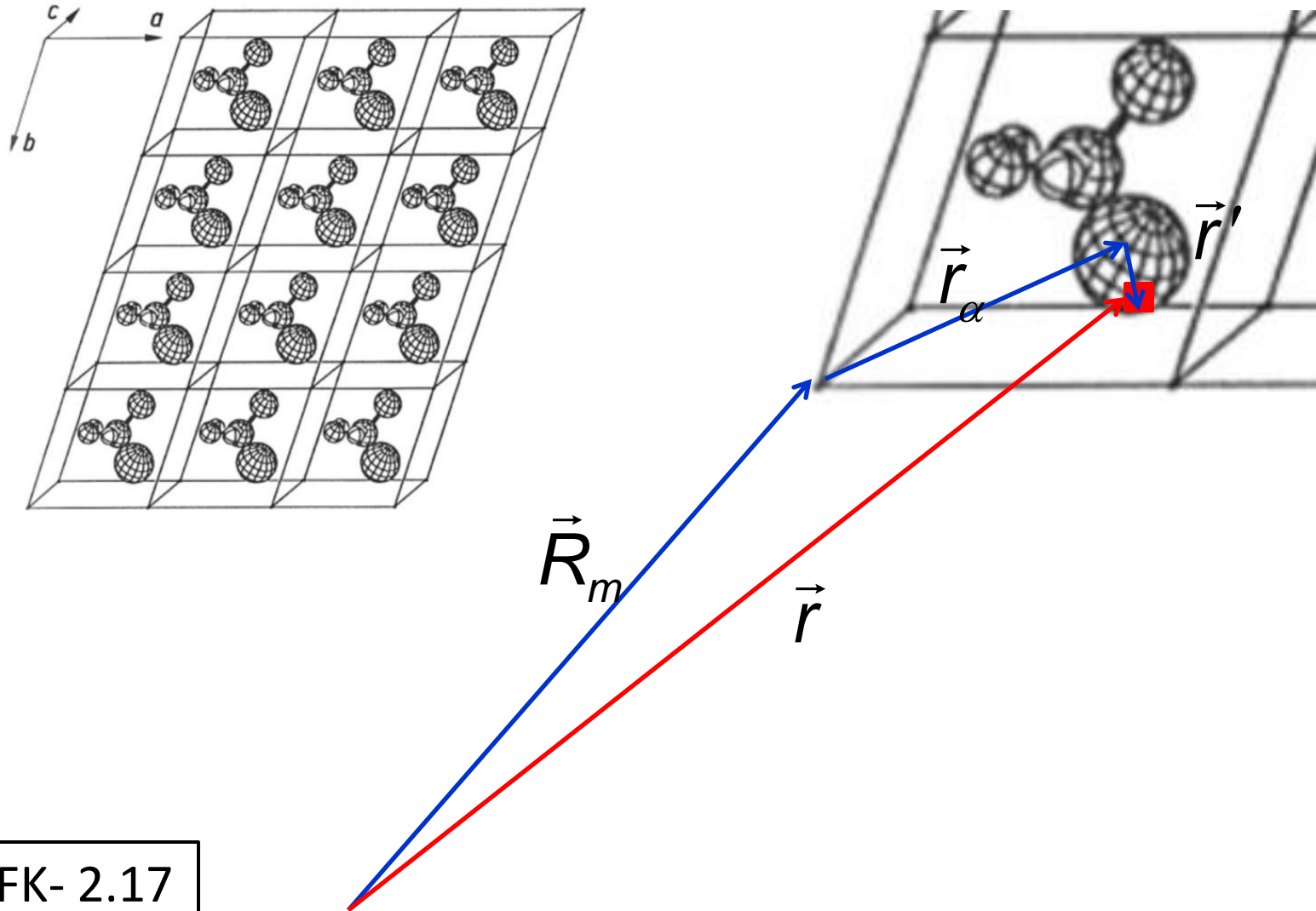
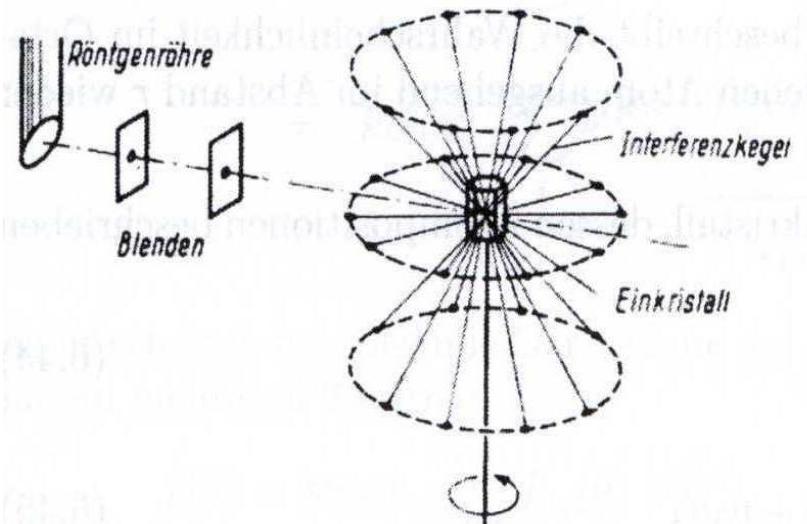
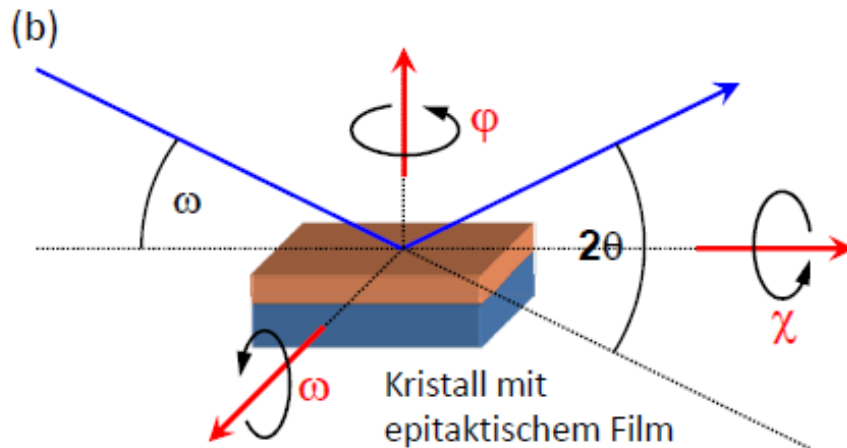
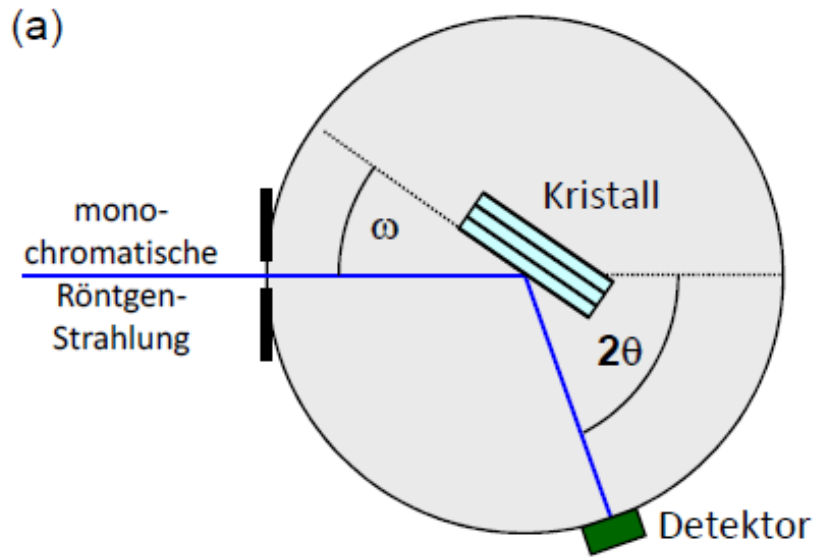


Fig-FK- 2.17

Drehkristall-Verfahren

Fig-FK- 2.18



Debye-Scherrer-Verfahren

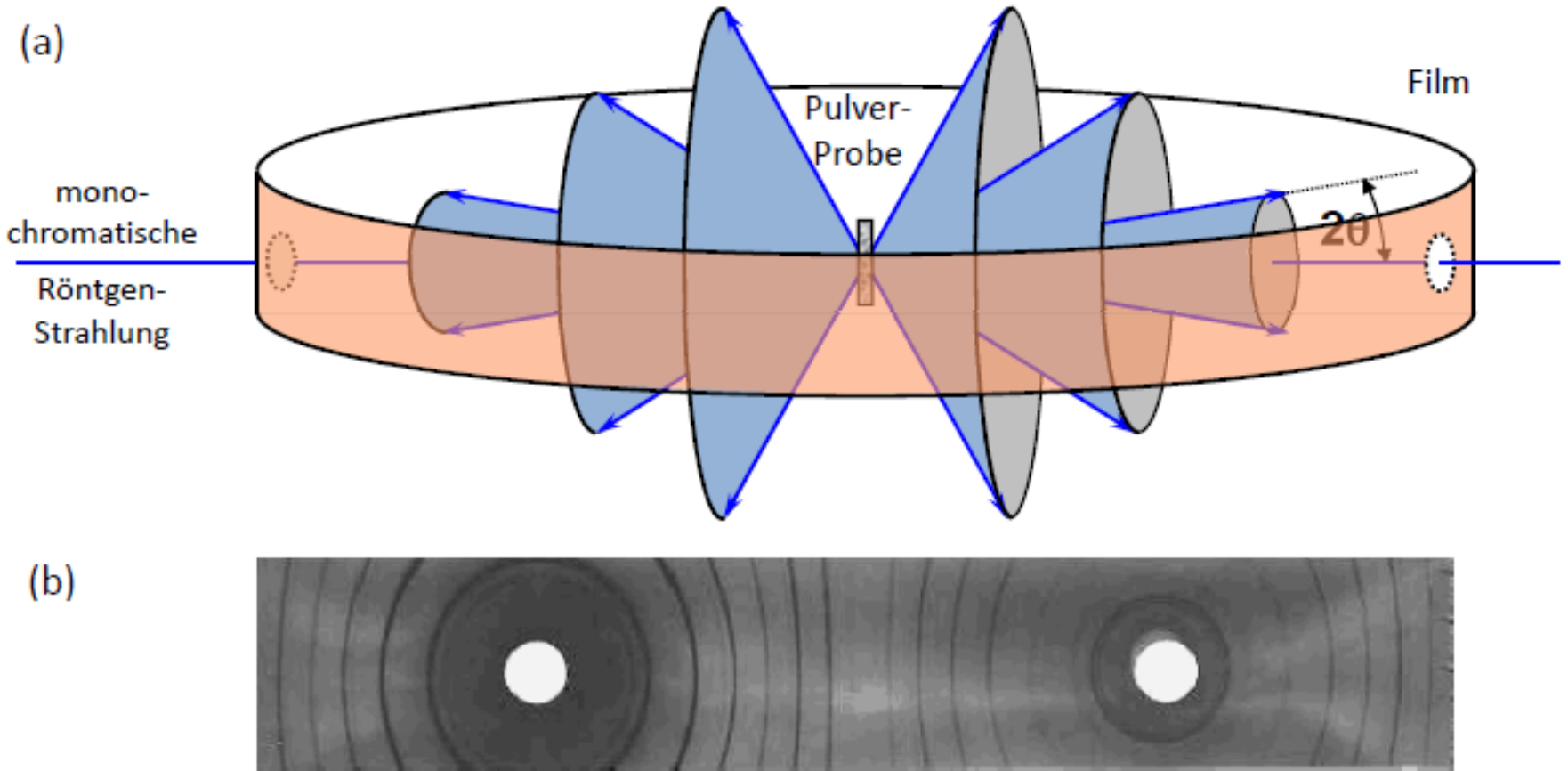


Fig-FK- 2.19

Laue-Verfahren

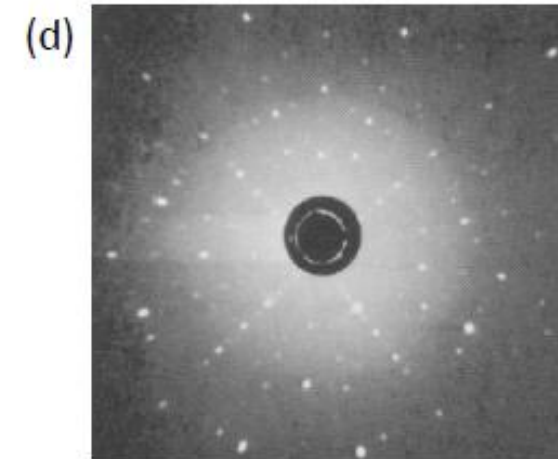
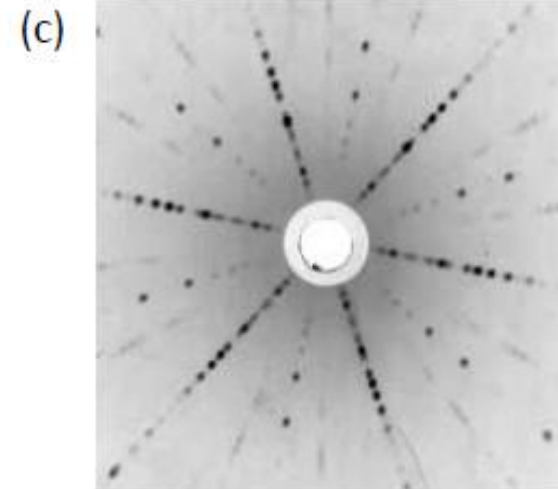
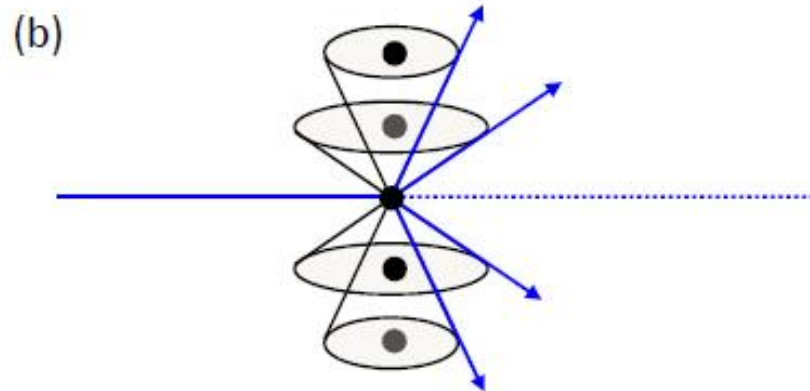
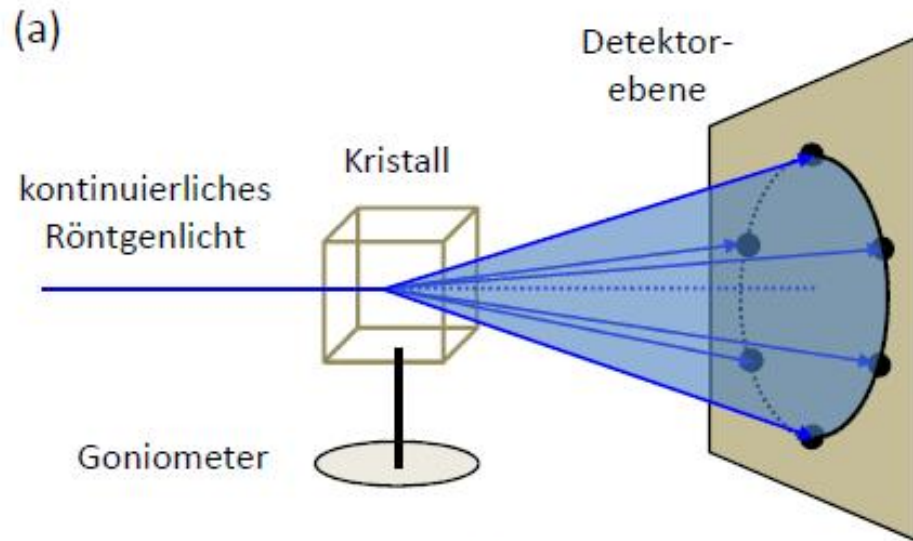
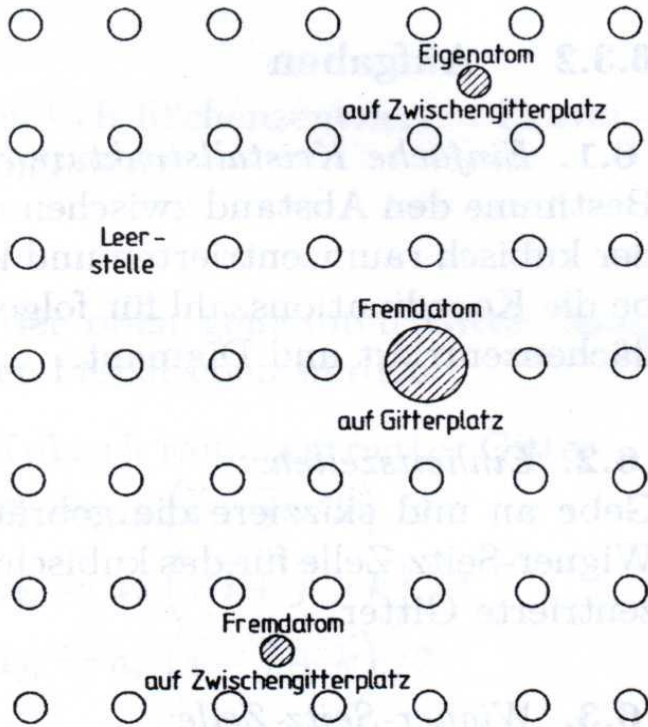


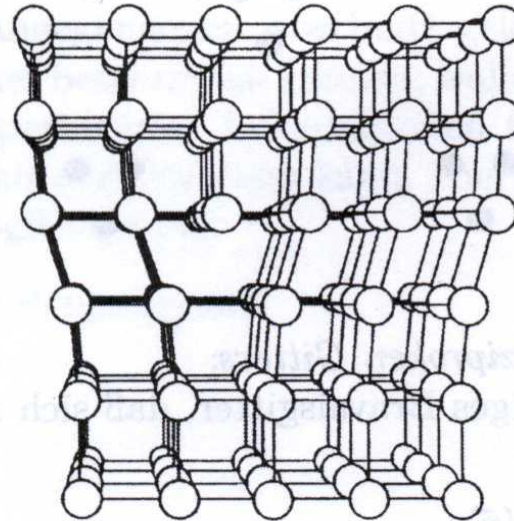
Fig-FK- 2.20

Defekte im Kristallgitter

Punktdefekte



Stufenversetzung



Schraubenversetzung

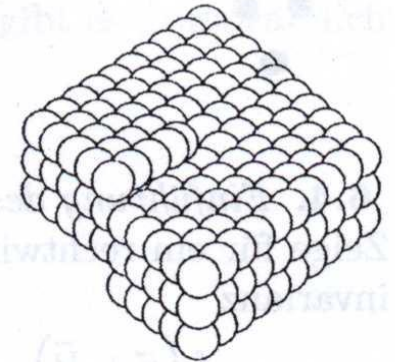
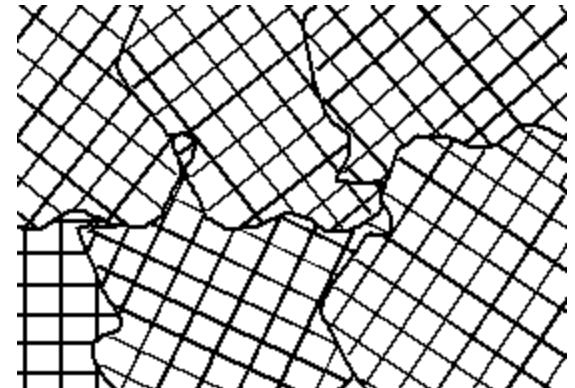
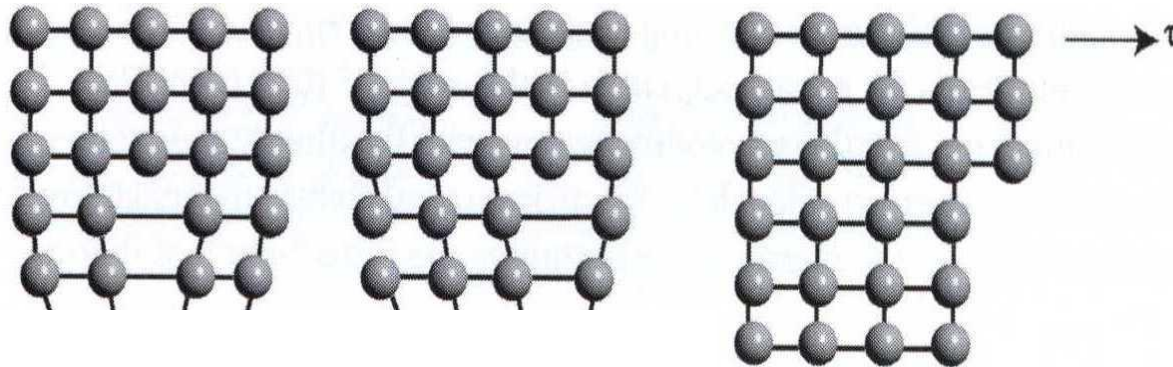


Fig-FK- 2.21

Flächendefekte:
Korngrenzen



Liniendefekt wandert unter Scherspannung durch Gitter



wenn er nicht von einer Verunreinigung aufgehalten wird: "pinning"

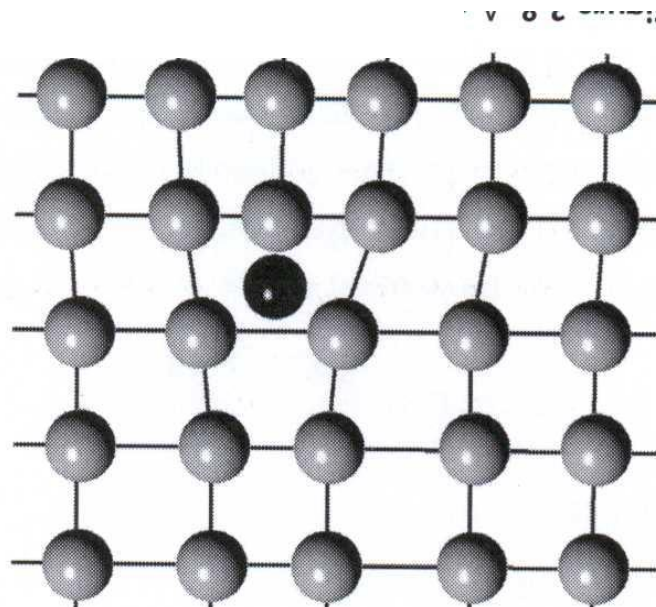


Fig-FK- 2.21